Search Notes

Application/Control No.	

10/727,594

Reexamination

DELBREIL ET AL.

Applicant(s)/Patent under

Examiner

Art Unit

JOHN J. LEE

2618

	SEARCHED		
Class	Subclass	Date	Examiner
455	403 561 562.11 509 11.9 19.1	12/22/2006	J.L
709	224	12/22/2006	J.L
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

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